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FR201GP THRU FR207GP

Features

- Low Cost
- Low Leakage
- Low Forward Voltage Drop
- High Current Capability
- Fast Switching Speed For High Efficiency
- Glass Passivated Junction

Maximum Ratings

- Operating Temperature: -55°C to +150°C
- Storage Temperature: -55°C to +150°C

Catalog Number	Device Marking	Maximum Recurrent Peak Reverse Voltage	Maximum RMS Voltage	Maximum DC Blocking Voltage
FR201GP	---	50V	35V	50V
FR202GP	---	100V	70V	100V
FR203GP	---	200V	140V	200V
FR204GP	---	400V	280V	400V
FR205GP	---	600V	420V	600V
FR206GP	---	800V	560V	800V
FR207GP	---	1000V	700V	1000V

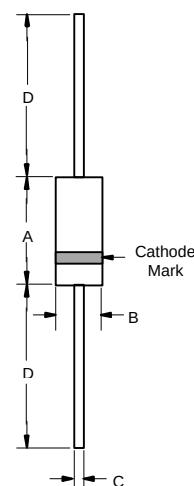
Electrical Characteristics @ 25°C Unless Otherwise Specified

Average Forward Current	$I_{F(AV)}$	2 A	$T_A = 55^\circ\text{C}$
Peak Forward Surge Current	I_{FSM}	60A	8.3ms, half sine
Maximum Instantaneous Forward Voltage	V_F	1.3V	$I_{FM} = 2.0A$; $T_A = 25^\circ\text{C}$
Maximum DC Reverse Current At Rated DC Blocking Voltage	I_R	5.0μA 100μA	$T_A = 25^\circ\text{C}$ $T_A = 100^\circ\text{C}$
Maximum Reverse Recovery Time FR201GP-204GP FR205GP FR206GP-207GP	T_{rr}	150ns 250ns 500ns	$I_F=0.5A$, $I_R=1.0A$, $I_{rr}=0.25A$
Typical Junction Capacitance	C_J	40pF	Measured at 1.0MHz, $V_R=4.0V$

*Pulse Test: Pulse Width 300μsec, Duty Cycle 1%

2 Amp Glass Passivated Fast Recovery Rectifier 50 to 1000 Volts

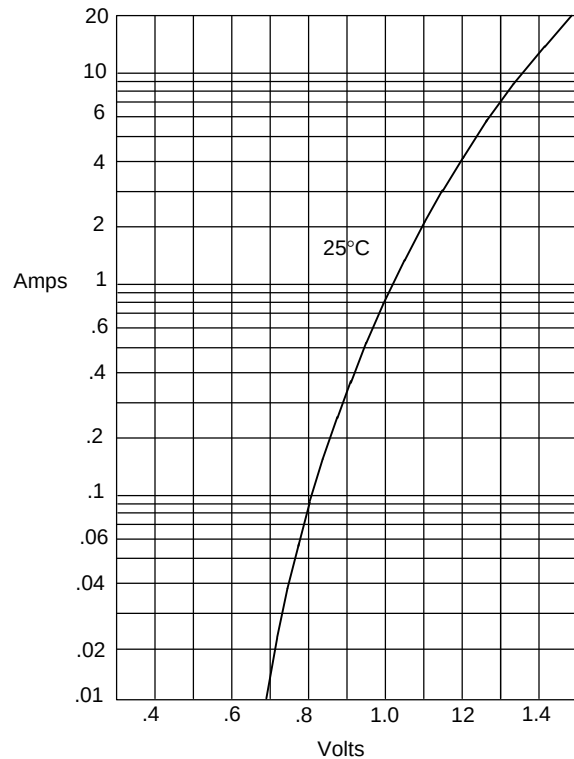
DO-15



DIMENSIONS					
DIM	INCHES		MM		NOTE
	MIN	MAX	MIN	MAX	
A	.230	.300	5.80	7.60	
B	.104	.140	2.60	3.60	
C	.026	.034	.70	.90	
D	1.000	---	25.40	---	

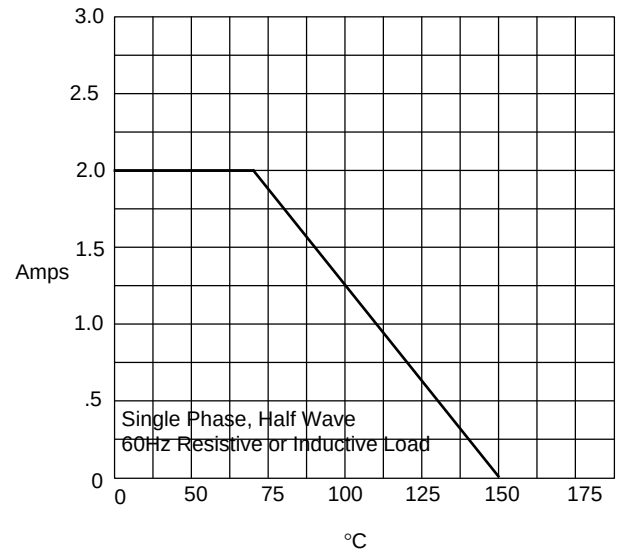
FR201GP thru FR207GP

Figure 1
Typical Forward Characteristics



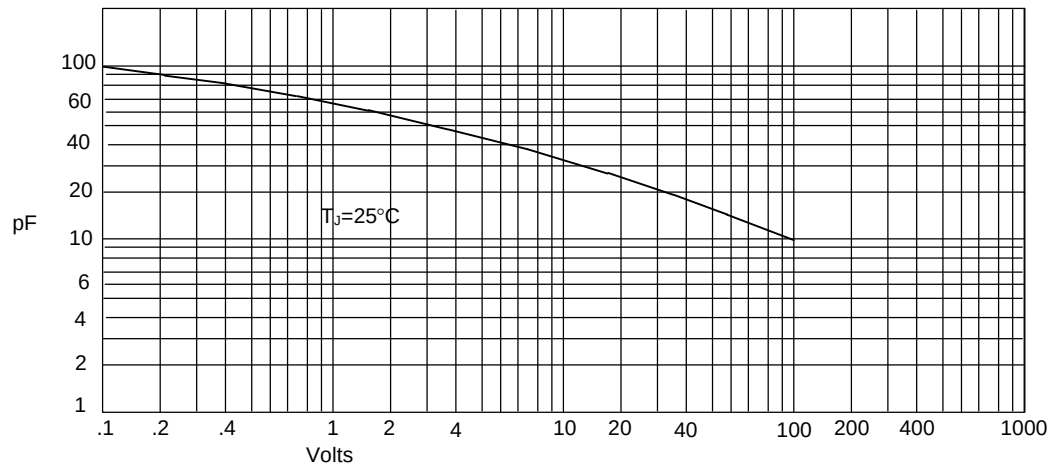
Instantaneous Forward Current - Amperes versus
Instantaneous Forward Voltage - Volts

Figure 2
Forward Derating Curve



Average Forward Rectified Current - Amperes versus
Ambient Temperature - $^\circ\text{C}$

Figure 3
Junction Capacitance



Junction Capacitance - pF versus
Reverse Voltage - Volts

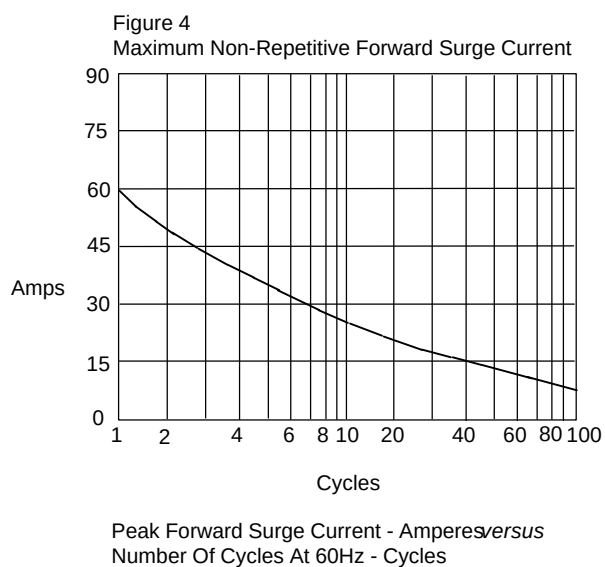


Figure 5
Reverse Recovery Time Characteristic And Test Circuit Diagram

